

Specification for plasma cleaner for electron microscopy sample preparation

NASA LaRC is seeking a solution for plasma cleaning of samples and specimen holders for use in electron microscopy analysis. The required features:

- Ability to clean scanning and transmission electron microscope specimens, specimen holders, and stubs
- Ability to clean side entry specimen holder for Philips CM 200 transmission electron microscope
- Ability to accommodate large objects (up to 3.5" in diameter)
- Ability to mix multiple gases for custom cleaning environments
- Oil-free vacuum system with load lock for rapid sample transfer